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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Complete if Known	
		Application Number	10/616,080
		Filing Date	July 8, 2003
		First Named Inventor	Mykhailo SHRIBAK
		Art Unit	2877
		Examiner Name	Nguyen, Tu T.
Sheet 1 of 2	Attorney Docket Number	34250-54	

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind-Code ² (if known)			
TN	AA	US-6,501,548	12-31-2002	Oldenbourg	
TN	AB	US-5,521,705	05-28-1996	Oldenbourg et al.	
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ Number ⁴ Kind-Code ⁵ (if known)				
TN	AC	GB 2 310 925	09-10-1997	Glazer et al.		

Examiner Signature	/Tu Nguyen/	Date Considered	09/21/2006
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Substitute for Form 1449/PTO		Complete if Known	
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Sheet	2 of 2		

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
TN	AD	E. A. Patterson, W. Ji, and Z. Fwang, "On Image Analysis For Birefringence Measurements in Photoelasticity", <i>Optic Laser Engineering</i> , 28, pp. 17-36, 1997	
	AE	S. Inoué, "A Method For Measuring Small Retardations of Structures in Living Cells", <i>Exp. Cell Res.</i> 2, pp.513-517, 1951	
	AF	S.Inoué and R. Oldenbourg, <i>Microscopes</i> , in <i>Handbook of Optics</i> , M. Bass, Editor. 1995, McGraw-Hill, Inc.: New York. pp. 17.1-17.52	
	AG	M. Noguchi, T. Ishikawa, M. Ohno, and S. Tachihara, "Measurement of 2D Birefringence Distribution," in <i>International Symposium on Optical Fabrication, Testing, and Surface Evaluation</i> , Jumpei Tsujiuchi, ed., Proc. SPIE 1720, 367-378, 1992	
	AH	Y. Otani, T. Shimada, T. Yoshizawa, "The Local-Sampling Phase Shifting Technique For Precise Two-Dimensional Birefringence Measurement", <i>Optical Review</i> , 1(1), pp.103-106, 1994	
	AI	J. L. Pezzanitti, and R. A. Chipman, "Mueller Matrix Imaging Polarimetry", <i>Opt. Eng.</i> 34(6), pp.1558-1568, 1995	
	AJ	Y. Zhu, T. Koyama, T. Takada, and Y. Murooka, "Two-Dimensional Measurement Technique For Birefringence Vector Distributions: Measurement Principle," <i>Appl. Opt.</i> 38, pp. 2225-2231, 1999	
	AK	A. M. Glazer, J. G. Lewis, and W. Kaminsky, "An Automatic Optical Imaging System For Birefringent Media," <i>Proc. R. Soc. Lond. A</i> 452, pp. 2751-2765, 1996	
	AL	M. I. Shribak "Autocollimating Detectors of Birefringence", in <i>International Conference on Optical Inspection and Micromasurements</i> , Christophe Gorecki, Editors, Proc.SPIE 2782, pp.805-813, 1996	
TN	AM	M. I. Shribak, Y. Otani and T. Yoshizawa, "Return-Path Polarimeter For Two Dimensional Birefringence Distribution Measurement", <i>Polarization: Measurement, Analysis, and Remote Sensing II</i> , Dennis H., Goldstein; and David B. Chenault; Eds. Proc., SPIE 3754, pp. 144-149, 1999	

Examiner Signature	/Tu Nguyen/	Date Considered	09/21/2006
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